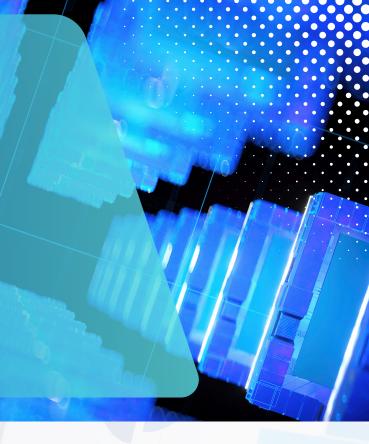


# 3D Thin Film Metrology Workshop

**THURSDAY, 26 JUNE 2025** 

Parnas Hotel Jeju Island, South Korea



#### **ABOUT WORKSHOP**

Join experts, researchers, and industry leaders for a one-day workshop on thin film metrology in high aspect ratio (HAR) structures, featuring the latest in ALD applications, conformality analysis, and advanced measurement techniques.

### Why Attend?

- Discover the latest tools and methodologies for 3D thin film metrology.
- · Learn from top researchers and engineers in the field.
- · Engage in hands-on training and discussions.

## Registration Details

- Fee: €250 (includes lunch, coffee, refreshment, and all workshop materials)
- Register now from here

Spaces are limited. Secure your spot today!



# Program at a Glance

Time	Activity
09:30–10:30	Get-together (Coffee and light snacks)
10:30–10:45	Welcome & Opening Remarks
10:45–11:30	Keynote Presentation: Advanced solutions for thin film process control
11:30–12:30	Hands-on Session with PillarHall test chip
12:30–14:00	Lunch & Business break
14:00–14:45	Presentation: Challenges and best practices in conformality measurement in HAR structures
14:45–15:00	Coffee break
15:00–16:00	Round table Discussion: Challenges in Sub-Angstrom Measurements + Q&A
16:00-19:00	Refreshment

#### **Additional Information:**

- Limited seats available early registration is recommended.
- Official language: English (Korean interpretation available).



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